## Simbol-X calibration issues

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From the calibration point of view Simbol-x presents 3 main non-standard issues

- Focusing optics at very high energy (End2End)
- Mirror and detector are not rigidly connected (End2End)
- Very large focal length (the most critical, Mirror Module + End2End)


## Non-standard calibration: the energy band

Monochromatic energies in the 20-80 keV energy band
Few lines; mono-chromator (double crystal difractometer) is an option
Otherwise we could use only continuum


Figure 5. Line at nominal 30 keV obtained with the fixed-exit monochromator. See text.


Figure 6. Line at nominal 45 keV obtained with the fixed-exit monochromator. See text.

## Non-standard calibration: line of sight calibration



Detector
The detector satellite (DSC), carrying the focal plane assembly, controls its position with respect to the Mirror satellite within control boxes of $+/-3 \mathbf{c m}$ in

Line Of Sight longitudinal and $+/-0.5 \mathbf{c m}$ in lateral.


20 arcsec


## Non-standard calibration: the focal length (studied by O.Citterio, S.Basso, D.Spiga)

Source finite distance problems (for large FL ~ 20m):

- A_eff loss (single reflection)
- Parabola angle $=$ hyperbola angle

FP displacement

- Focal spot blurring


## Problem 1: loss of effective area



X-rays reflected near the parabola front-end do not undergo the reflection and are not focused on the X-ray detector this causes loss of effective area .

## Problem 1: loss of effective area



## Problem 2: different incidence angle



A source at infinity is focused by 2 reflections with the same angle $\alpha$ (which is the angle between parabola and hyperbole)

A source at distance $D$ has a divergence of $\beta=R / D$ at the entrance of a mirror with radius $R$. The photon is reflected with 2 different angles $\alpha+\beta$ on the parabola and $\alpha-\beta$ on the hyperbole

Because $\beta / \alpha \sim 4 \mathrm{x}$ focal length/ source distance in the case of Simbol X at Panter this effect is not negligible

## Problem 2: different incidence angle means different reflectivity

W/Si graded multilayer, $\alpha=0.16 \mathrm{deg}$


Source at $120 \mathrm{~m}(\mathrm{r}=115 \mathrm{~mm})$


The departure of the actual incidence angles from the nominal one has to be considered when interpreting the effective area data, as it changes significantly the measured reflectivity.

## Other problems

Increase of the focal length with respect to the nominal one:

$$
f_{1}=\frac{D f}{D-f}
$$

$D=$ distance mirror-source; e.g. $f=10 \mathrm{~m}, \mathrm{f}_{1}=10.88 \mathrm{~m}$,

$$
\mathrm{f}=20 \mathrm{~m}, \mathrm{f}_{1}=24.44 \mathrm{~m}
$$

A slight blurring of the image even at the focus $f_{1}$

$$
H E W_{D}=4 \frac{L_{p}}{f} \tan \left[\alpha\left(\frac{f}{D}\right)^{2}\right]
$$

$L_{p}=$ length of the parabola, $\alpha=$ nominal incidence angle;
e.g. $L_{p}=30 \mathrm{~cm}, \mathrm{f}=10 \mathrm{~m}, \alpha=0.2 \mathrm{deg}, \mathrm{HEW}_{\mathrm{D}}=0.6 \mathrm{arcsec}$
e.g. $L_{p}=30 \mathrm{~cm}, f=20 \mathrm{~m}, \alpha=0.2 \mathrm{deg}, \mathrm{HEW}_{\mathrm{D}}=1.1 \mathrm{arcsec}$

## Solution for a single shell



If we adopt a pencil beam setup, we can select a thin beam (a few 10 arcsec divergence) and correct the beam divergence for a shell sector in order to make the two incidence angles equal (and equal to the on-axis incidence angle!)

Once the correct angles are set, all the optic performance (focusing + effective area) can be measured by spinning the optic around its axis, illuminating all sectors under the same conditions, and superposing all the images in the focal plane.

## Solution for the whole optical module: the jig



## End2End calibration dataset (the swift scheme)

## DATASET:




OUTPUT:

- PSF Model
- Effective Area
- Energy resolution
- ARF + RMF
with 5\% of accuracy


## Standard calibration lla: the PSF calibration



Given ~10000 counts, for each energy and position, the accuracy in the PSF model reconstruction is < 5\%

Assuming a King profile A speculation more than a simulation....



## Standard calibration IIb: HEW verification



Given ~10000 counts, the accuracy in the HEW measurement is $<5 \%$

Assuming a King profile: A speculation more than a simulation....



## PSF model importance



In XRT the dependence of the PSF from the off-axis angle is very shallow, because the telescope is de-focussed

The energy dependence is also very shallow, because the effective area is all concentrated in a small energy band (0.5,2.0 keV)

For SIMBOL-X the situation is very different: it will collect photons over a wide energy band. Therefore the PSF calibration as function of energy will be very important.

## SWIFT XRT PSF in orbit

2 different sources, with different spectra and off-axis angle, but same



For XRT It is very easy to model the off-axis angle and energy dependence, because this dependence is very shallow

## Standard calibration: effective area


~10000 counts,
ch energy the statistical uncertainties in the effective are $\sim 1 \%$
we have to take into account:
ures between calibration energies
ertainties in the input spectrum and count rate

## Swift-XRT Effective area from ground to orbit



## TIMING REQUIREMENTS

$$
\begin{aligned}
& \text { Total time }=\text { N_ene } * \text { N_pos * counts / rate@ccd+[ N_ene * dt_ene + N_pos *dt_pos }] \\
& \text { N_en. }=20 \text { N_pos }=33 \text { counts }=10000 \text { rate_at_ccd }=1000 .
\end{aligned}
$$

$\rightarrow$ total time [standard] $=2 \mathrm{hrs}+$ dead time
$\rightarrow$ total time [pencil beam] $=100 *($ total standard time $)=200 \mathrm{hrs}+$ dead time pencil beam
$\rightarrow$ total time [relative position] $=5^{*}($ total pencil beam $)=1000 \mathrm{hrs}+$ dead time relative position

## In-flight Calibration




## DA calibration (model) philosophy

| What (model) | Why (Goal) | When |
| :---: | :---: | :---: |
| Breadboard | EMI/EMC compatibility <br> tests | End 2008 |
| Demonstrator | Separated chains <br> functionality validation | End 2009 |
| SM | Structural validation | $2008-2009$ |
| STM | Mechanical, thermal and <br> integration validation | 2009-2010 |
| EM | Electrical design <br> validation | mid-2010 |
| QM | Fualification | 2012 |
| FM | Fly |  |

## MU calibration (model) philosophy

| What (model) | Why (Goal) | What | When |
| :---: | :---: | :---: | :---: |
| STM | Optical <br> validation after <br>  <br> thermal cycles | 4 "standard" + <br> 96 dummy <br> shells | End 09 |
| QM | Scientific <br> performance <br> validation | 10 "standard" <br> shells + <br> 90 "dummy" <br> shells | 11 |
| FM | Fly | 12 |  |

